

# **Introduction to Worst Case Loading and Timing Analysis**

## **Introduction**

- **Timing** is probably more important to the success of a microcomputer design than it is to **Comedy** !!!
- While it is possible to build and debug a single computer system, e.g. a 1-off or prototype, it is significantly more difficult to be able to guarantee that a **batch** of such systems will all work especially when you factor in the **entire range** of possible **conditions** that the components and system may be exposed to.
- For example, the following factors can all make the exact **run-time operation** of each and every mass-produced **chip** and circuit **board unique**.
  - **Temperature.**
  - **Electrical supply voltage.**
  - **Capacitive loading.**
  - **Variations in component Min-Max** timing due to production tolerances
  - **Layout of chip/PCB (e.g. revisions).**

## ***Worst Case Loading and Timing Analysis***

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- There are many designs in **production** right now that probably have a significant number of **unidentified potential failures** due to a lack of a **worst case loading** and **timing analysis** during **design**.
- Such failures, may be picked up during **simulation** and/or **testing** of **initial prototypes** or, as a last resort, in **post-production testing** as they come off the assembly line (assuming you are *rigorous enough*) but depends on volume and intended application – e.g. safety critical systems, as to whether all get rigorously tested.
- Worst case, the failures may not show up in significant numbers until the product is out in the **field** where it may need to be **recalled** and **replaced** leading to major expense and loss of “**good will**” with customers.

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## **Reasons for Timing Variation: Min-Max Component Tolerances**

- The most common cause of failure is variations in operational **Timing**
  - Maybe **2%** of all systems fail simply because they were built from a random batch of chips whose **timing characteristics** were at the **extreme edges** of manufacturers "**min-max**" **tolerances**.

When a system is put together using these "**unlucky**" components, the timing of critical signals as they pass through gates in the circuit and around the PCB may be altered just enough to result in **races**, **hazards** and **glitches**. Worst case it may result in the **clock** to a flip-flop **arriving before** its **data**, resulting in failed operation. Most designers only build a few prototypes so they mostly miss this.

These types of failures are hard to pick up just by observing the "**actual timings**" of a few random prototypes, or even during production when perhaps just **5%** of boards are thoroughly tested.

Good **simulators** can help in the design phase of say a **chip** (e.g. an **FPGA** or **ASIC**), but it is more difficult to simulate a **complete system** where **accurate simulation models** of each manufacturer's chips may not exist, or more significantly, where the effects of **PCB**, **component** and **track layout** can be hard to simulate.

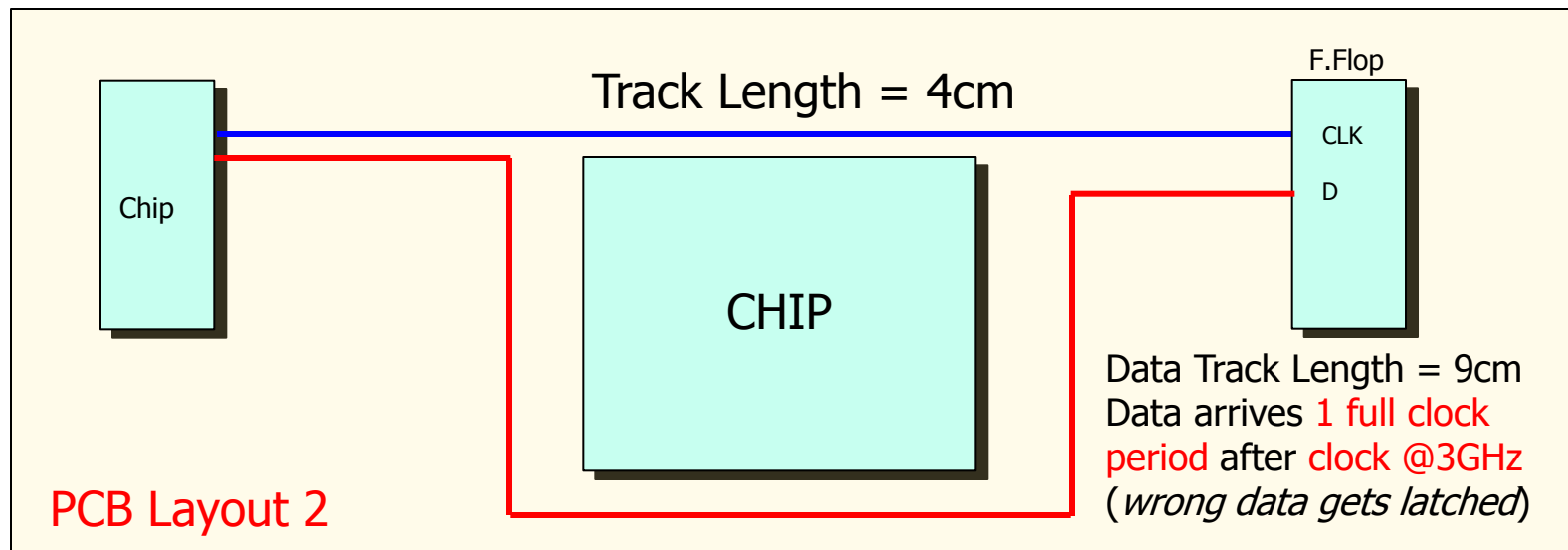
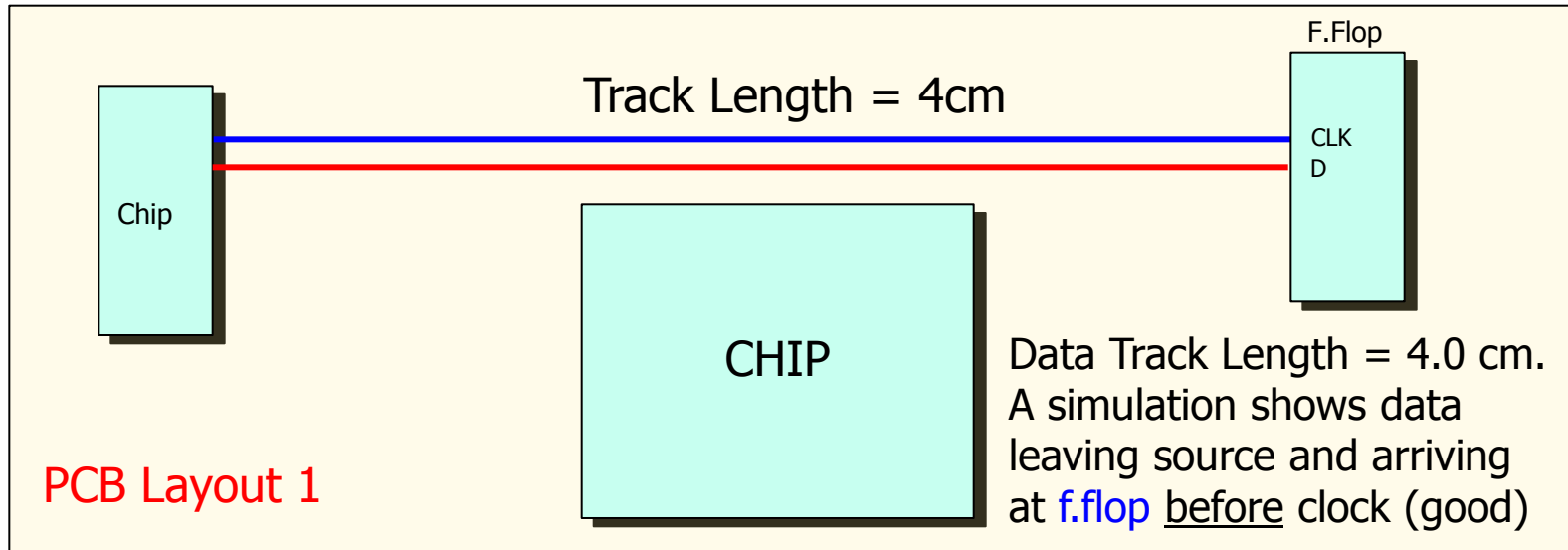
- Good engineers therefore need a handle on factors that can influence the timing in their design, particularly for aspects that are hard to simulate.

## **Other effects that lead to timing variation**

- **Revised PCB Layout:** Designs have been known to fail, simply because the manufacturer **revised** the layout of a PCB, resulting in a critical/marginal signal being **routed** differently in the new design which **subtly altered it's timings**. The layout of very high speed circuits onto PCBs is a real skill and best left to someone with experience.
- **RevisedChip Layout:** Similarly **FPGA** designs with tight timing tolerances in **Quartus** can fail when a different “**fitter**” algorithm is used to lay out the interconnect within the chip, or when new circuitry is added that causes the fitter to change layout. The system is only as good as the simulation, which in Quartus means it ends at the pins of the FPGA. After that all bets are off as it travels down tracks on PCBs etc.
- Admittedly, the likelihood of such problems occurring at **low clock speeds** (e.g. <10MHz) is relatively small, but beyond 1GHz, a variation in the length of a PCB track, or an interconnect in an ASIC by even just a few **mm** can be critical.
- For example a **3Ghz** has a wavelength =  $\sim 5\text{cm}$  on a PCB track (at  $\sim \frac{1}{2}$  speed of light). An oscilloscope placed in the middle of that track would show a signal “phase shifted” by **180** degrees. A signal at the **end** of the track is 1 **complete clock cycle** behind the same signal at the start of the track.
- If a PCB track carrying that **3Ghz clock** is shortened by say **1cm** then the active edge of the clock could easily be shifted such that it occurs **before** the **data** arrives !!

# Worst Case Loading and Timing Analysis

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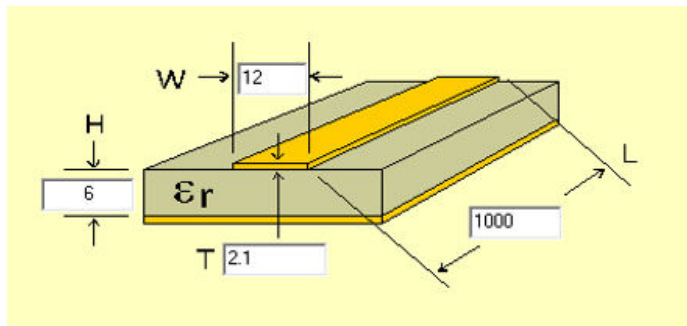


# Worst Case Loading and Timing Analysis

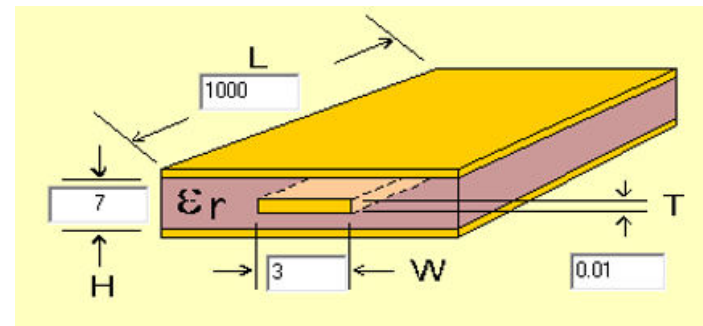
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## Reasons for Timing Variation: PCB construction material

- The speed at which a signal propagates along a PCB track is a function of the track **geometry** and the **material** from which it is constructed, i.e. its characteristic impedance  $Z_0$ . Two commonly used but different PCB construction techniques (**microstrip** and **stripline**) are shown below.



Microstrip



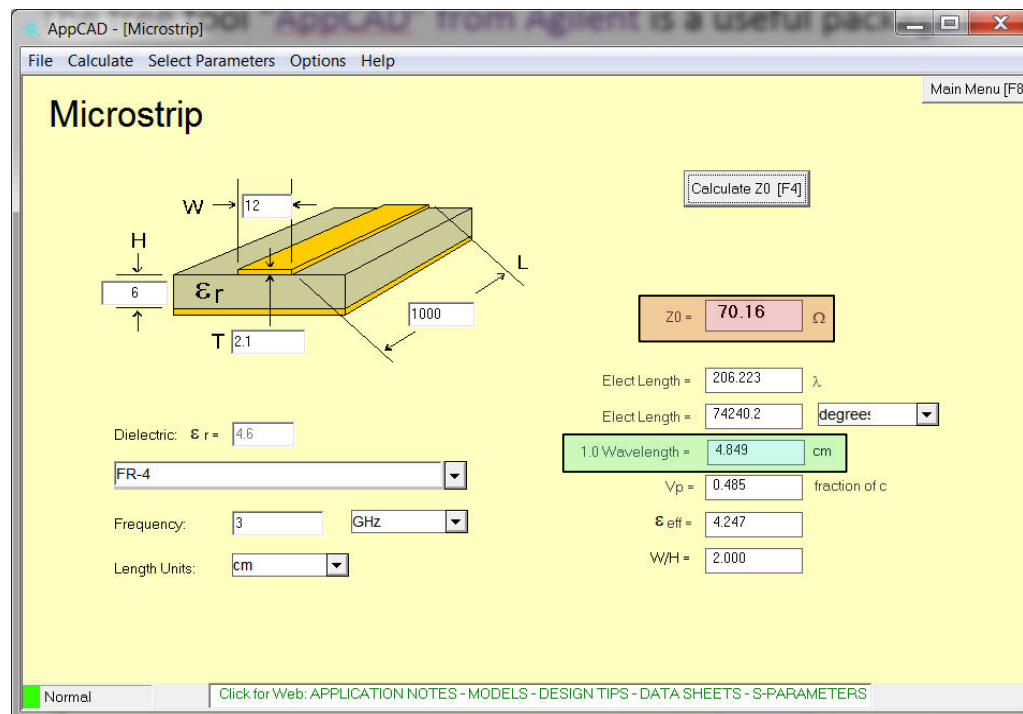
Stripline

SYMBOL	DESCRIPTION
H	Height of the dielectric
W	Width of the trace
L	Length of the trace
Frequency	The frequency on which the calculations are based
$Z_0$	Characteristic impedance of the trace
1.0 Wavelength	Wavelength $\lambda$ of the trace at the given frequency and the given effective dielectric $\lambda = \frac{3 \times 10^8 \text{ m/s}}{\sqrt{\epsilon_{\text{eff}}} \times f}$
$V_p$	Velocity of the signal on this trace with the given dimensions and frequency relative to the speed of light. The absolute velocity is calculated by $V_{p,\text{absolute}} = V_{p,\text{relative}} \times 3 \times 10^8 \text{ m/s}$
$\epsilon_{\text{eff}}$	Combination of the several dielectrics which surrounds the microstrip
W/H	Ratio between trace width and trace length

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- The free tool “AppCAD” from Agilent is a useful package to download and experiment with, when determining how dielectric, and track construction affect the propagation speed and characteristic impedance  $Z_0$  of a copper track on a circuit board.
- The example below shows an FR-4 Microstrip PCB ([en.wikipedia.org/wiki/Microstrip](http://en.wikipedia.org/wiki/Microstrip)) construction. FR4 is a glass-reinforced epoxy laminate sheets ([en.wikipedia.org/wiki/FR-4](http://en.wikipedia.org/wiki/FR-4)) the most common PCB construction material.
- Signal speed  $V_p$  is slightly less than  $\frac{1}{2}$  speed of light.
- Knowing the speed we can work out signal delay.

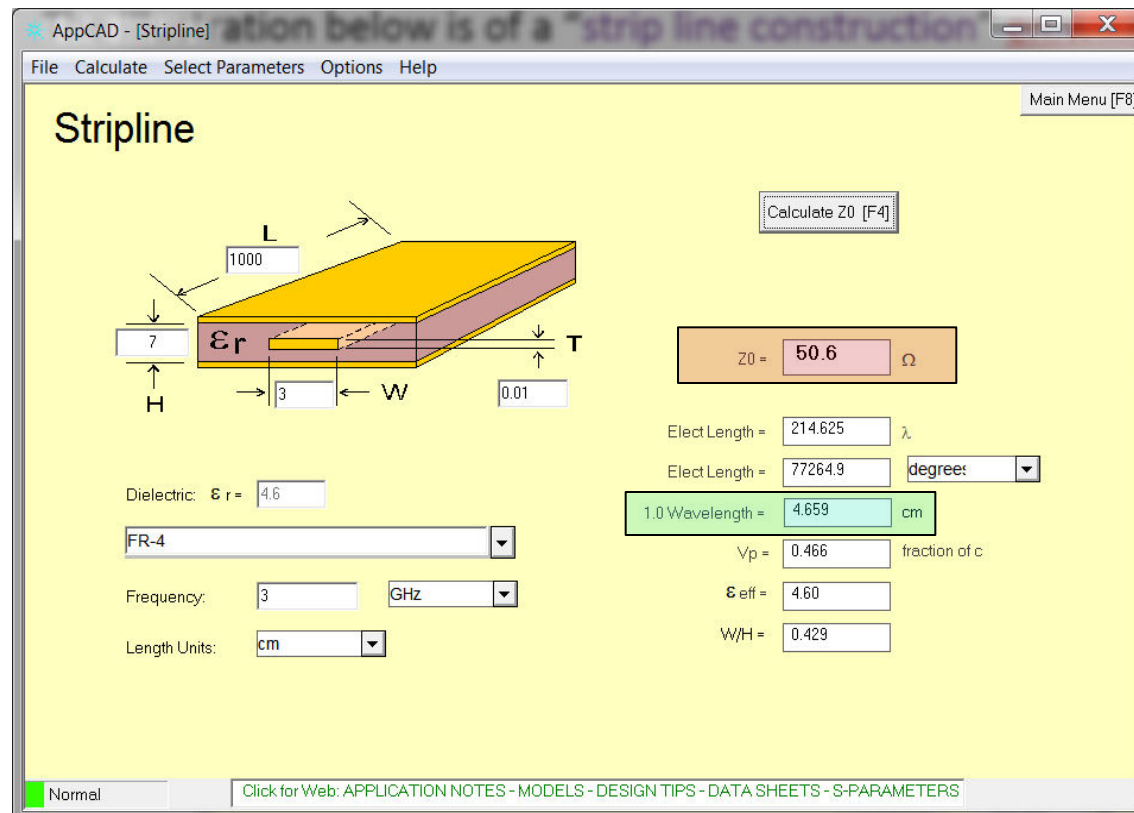




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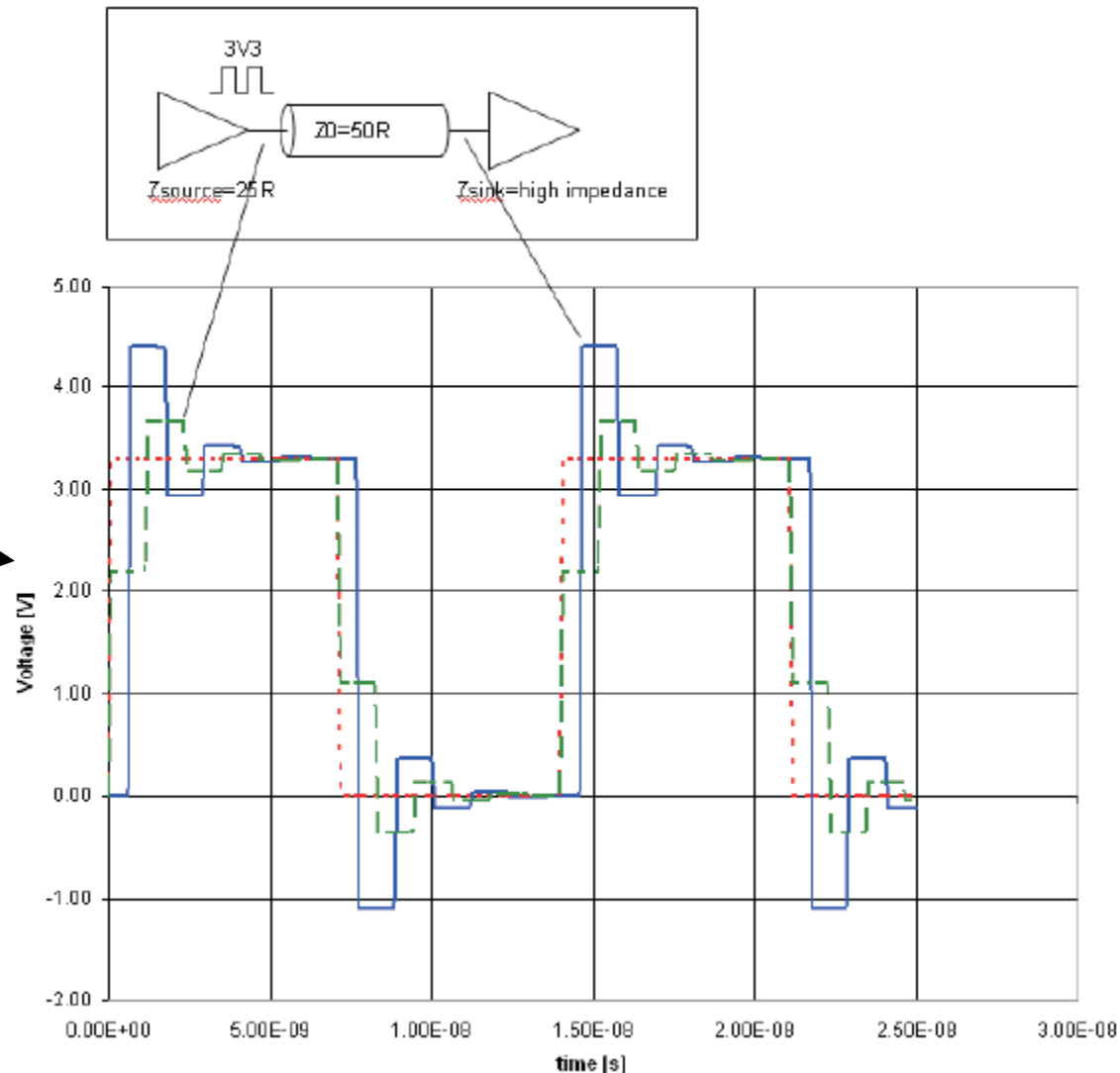
- The illustration below is of a “strip line construction” [en.wikipedia.org/wiki/Stripline](https://en.wikipedia.org/wiki/Stripline) which uses a flat strip of metal sandwiched between two [parallel ground planes](#). This technique, although more expensive to manufacture, leads to **better/reduced EMI** at higher frequencies compared to microstrip construction.
- Speed is slightly less than  $\frac{1}{2}$  speed of light.



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- Impedance **mis-matching** between chips and PCB tracks can lead to **reflections** of signals that exhibit fast rise/fall times.
- The effects of these reflections can lead to a **partial cancelling** of the propagating signal's "**voltage wave front**", i.e. the leading edge of the signal, resulting in slower rise/fall times (**red** signal is the source, **green** signal is entering PCB track, **blue** signal is at receiver) and hence increased propagation times (time to register a logic 0 or 1 at other end)
- We'll return to this subject in a later lecture.

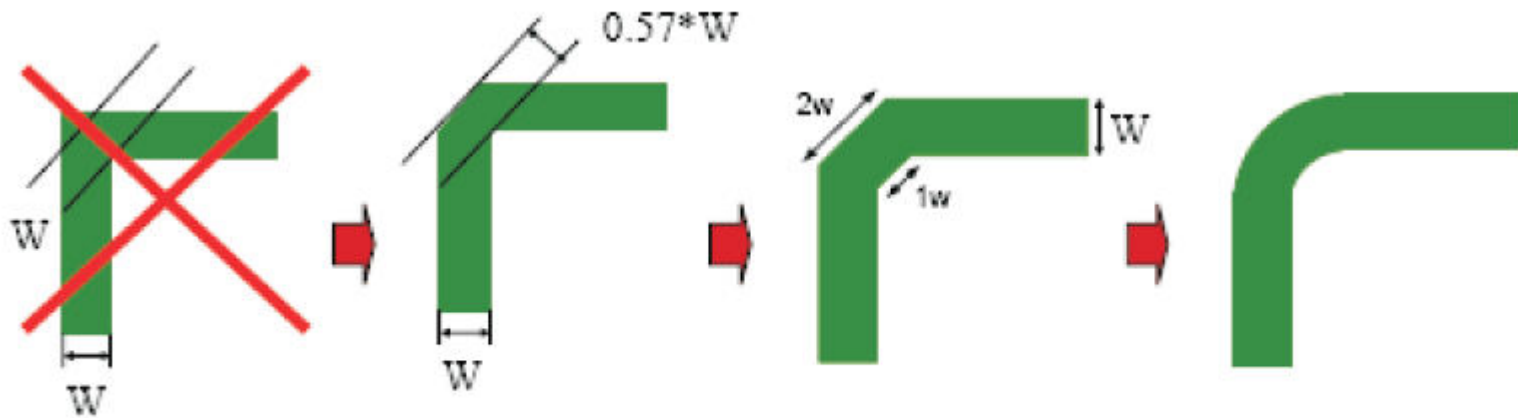


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## **PCB Track layout affects Propagation delay and also EMI**

- Layout of PCB tracks can also affect propagation delays of signal, particularly at sharp/abrupt corners where reflections back towards the source can occur.
- Abrupt corners can also lead to increased EMI at higher frequencies.
- Both undesirable side effects can be reduced by making the corner more “rounded”. Something to “bear in mind” when laying out a PCB.



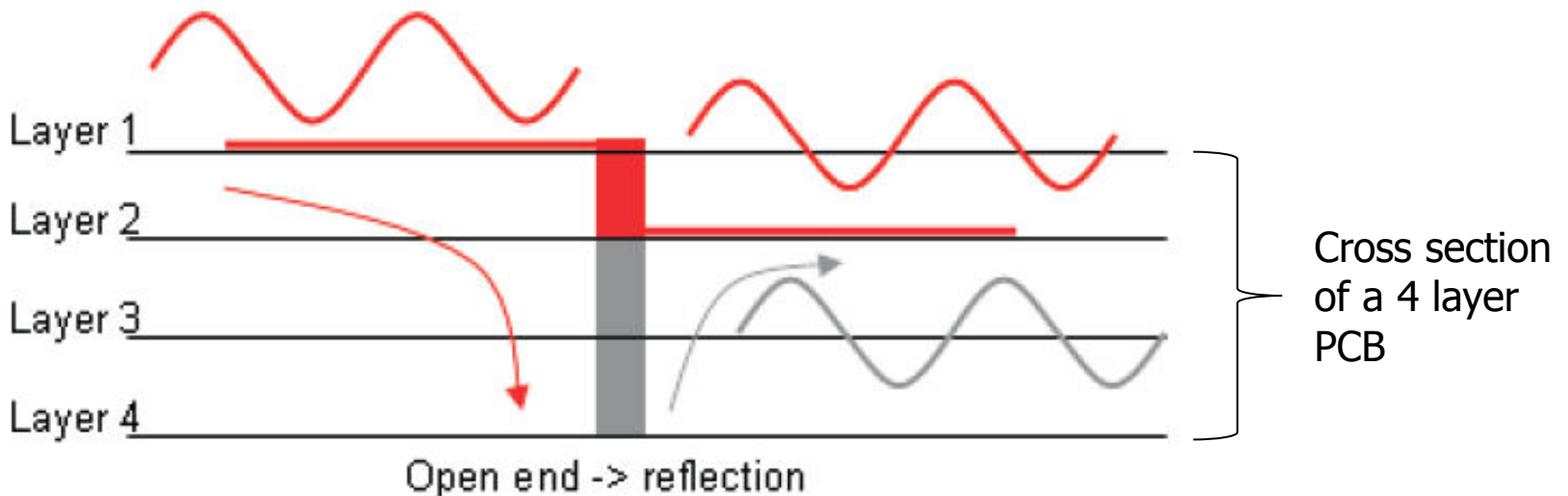
**Poor and Good Right Angle Bends**

## ***Worst Case Loading and Timing Analysis***

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Using “vias” on PCB tracks [http://en.wikipedia.org/wiki/Via\\_%28electronics%29](http://en.wikipedia.org/wiki/Via_%28electronics%29)

- The use of **vias** is essential in most PCBs to connect signals on one layer to signals/tracks on another and they generally pass right through the board.
- A PCB designer has to be careful using them as they add additional inductance and capacitance, giving rise to **reflections** due to the change in the characteristic impedance at each end of the via.
- Vias also increase the trace **length** (connections between layers) leading to further delays.



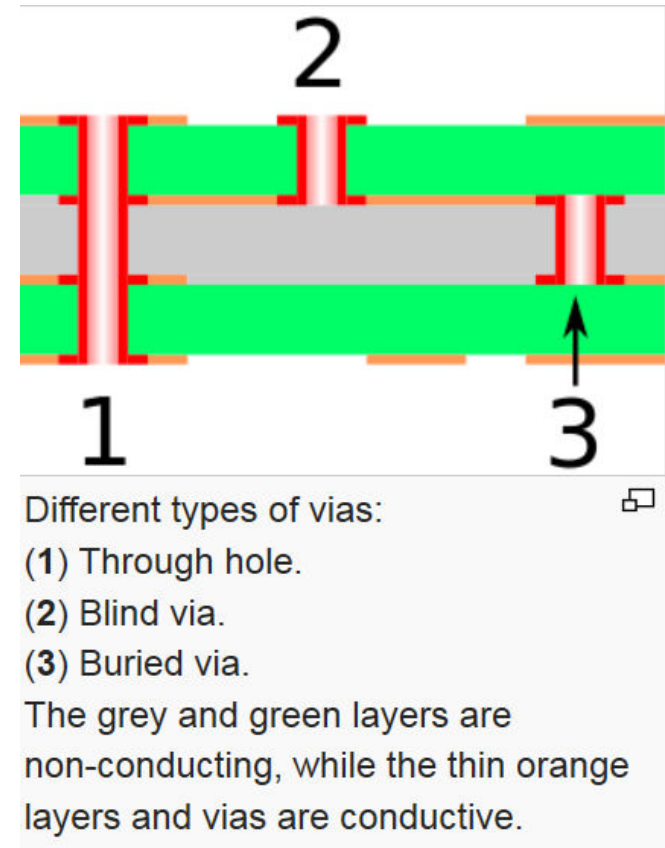
**Reflection Caused by Stubs in a Via**

# Worst Case Loading and Timing Analysis

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## Tips for routing tracks and the use of vias:

- Do **not** use 90° corners on tracks with **fast rise times**.
- Ensure tracks on different layers of the PCB are routed at 90 degree angles to each other (e.g. **east-west** on Layer 1, **north-south** on layer 2 etc.) to avoid signal coupling.
- To minimize crosstalk, the distance between two tracks on the same layer should be approximately **2 to 3** times the width of the track.
- **Differential** signal tracks should be routed as close as possible to get a **high coupling** factor – leads to **increased noise immunity** due to common mode rejection of noise.
- Do **not** use vias on traces with sensitive signals
- Consider stubs created by vias - use **blind** vias or **buried** vias.



## **Other Reasons for Timing Variation: Temperature, Power supply variations and Loading**

- Most manufacturers quote their chips **min-max timings** only for a **specified Temperature, Voltage** and **Capacitive load value**.
- Could you predict how your circuit timings will vary if these factors are altered? If you are lucky the manufacturer will tell you, if not then prepare for some failures if your design does not take these variations into account.
- Do you know for example what the actual **voltage** is, at the **power pins** of **every chip** on your PCB and what factors affect it? You may assume it's **5v** or **3.3v** etc. but have you actually **measured** it. What can you do to improve it?
- What is the **operational temperature** of your circuit?
- What is the **capacitive loading** on critical signals and how do all these things affect timing – more capacitive loading **slows** the **rise** and **fall** times of signals as the capacitance charges and discharges through the output resistance of the transistor driving the load?

# Worst Case Loading and Timing Analysis

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## Factors affect Propagation Time: Temperature

- Devices tend to get **slower** as **temperatures rise**, this is a physical effect, due to increased resistance change in Mosfets due to reduction in electron mobility, resulting in lower currents and slower switching times. This goes some way to explaining why computers fail as they get hotter, perhaps after they have been working OK for several mins.
- For some IC families, their propagation delays change by **~2nS** over the entire temperature range of **-50°C** to **+100°C** which is significant at very high frequencies.
- It also explains why “**Over clockers**” (who try to raise the clock frequency of their CPU above manufacturers recommended maximum *generating more heat*), often have to resort to liquid cooling to keep the chip functioning at it's fastest speed.
- Tests for propagation delays are generally quoted by the manufacturer at room temperature e.g. **25 degrees C** but you should consider the effect for other temperatures.

65nm CMOS Technology	Temp (°C)	Inverter	NAND2	NAND4	NOR2	NOR4
Average Delay (s)	25	1.54E-11	5.62E-11	8.65E-11	6.86E-11	1.35E-10
	125	2.08E-11	8.52E-11	1.32E-10	1.05E-10	2.05E-10
Delay Variation (%)		35.0	51.6	52.6	52.4	52.1

<http://ihome.ust.hk/~eekursun/papers/c25.pdf>

# ***Worst Case Loading and Timing Analysis***

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## **Factors affect Propagation Time: Power supply voltage**

- A change in propagation delay might also be expected as  $V_{cc}$  (supply voltage) varies between its **minimum** and **maximum** operational values, the exact value varies from chip to chip.
- Reduced supply voltage at the **chip** (*i.e. below manufacturers recommended operating voltage*) may be as a result of poor **power distribution** on the PCB. Wider power tracks or better still, separate **power/GND planes** lead to reduced power line resistance, which in turn leads to less voltage drop at the chip.
- Increased chip **voltages** lead to increased currents (*generating more heat and stressing the chip*), which allow the transistors to switch state more rapidly since the increased current leads to **faster charging/discharging** of signal capacitance (loads), i.e. it affects the **slew** rate of the device.
- **Over-clockers** often have to raise the motherboard voltage to achieve higher clock frequencies while force-cooling the resulting hotter circuit.
- Values quoted by the manufacturer are those for the device operating at its **recommended supply voltage**, if you know it will operate outside that, then ideally you take it into account.

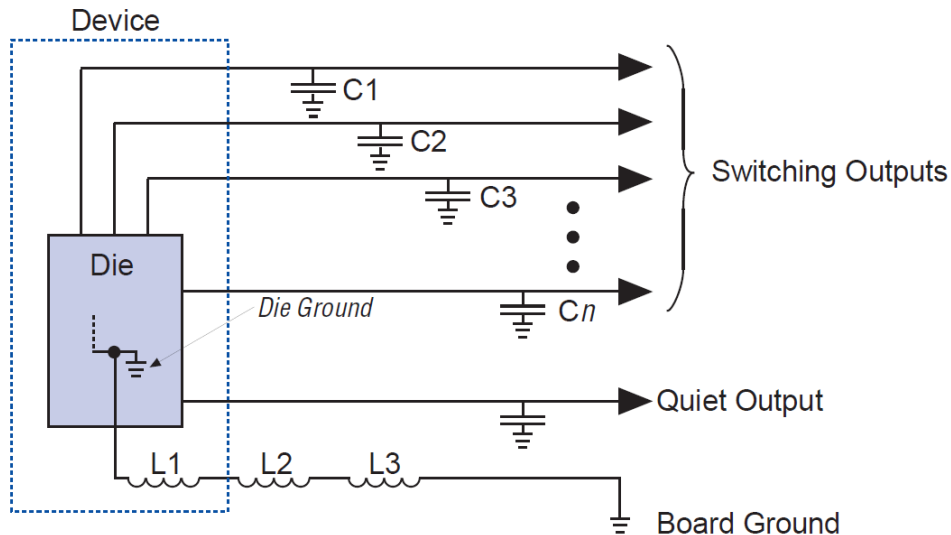


# Worst Case Loading and Timing Analysis

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## Factors affect Propagation Time: Number of outputs switching simultaneously

- The number of **output** pins that simultaneously switch from high to low within a chip can have an effect on the propagation delay of each individual output. e.g. an 8 bit counter rolling over from **11111111** to **00000000** is an example.
- This is due to the inherent **inductance** associated with the ground lines feeding the chip. The illustration below shows several output signals with inherent capacitance all currently charged to logic '1'. When they switch together a large momentary current is created as the chip tries to discharge those capacitors and the current flows via the **GND** pin.
- The inherent **inductance** of the Ground signal creates a **back emf** which can lead to a small reduction in the supply voltage inside the chip due to “**ground bounce**”. This results in momentarily smaller operating voltages, reduced slew rates and longer discharge times for the capacitors. **74AHCTxx** families add **250ps** per output switching.



**L1** = Inductance of bond wire in the chip from devices 'die' to the package pin

**L2** = Inductance of the package pin to the PCB ground signal. This is greatest when the device is placed in a socket

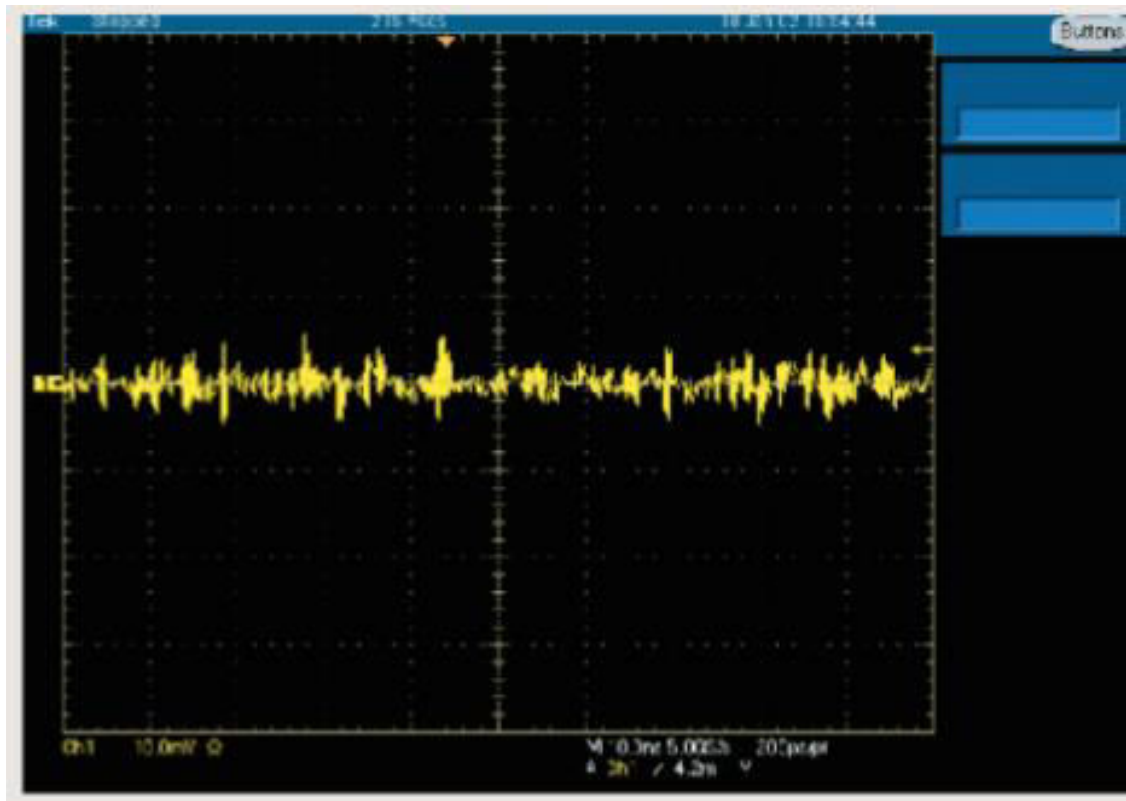
**L3** = Inductance of the PCB track back to the power supply ground reference.

Ground bounce can also cause “quiet output” signals (those at logic 0) to momentarily rise which could trigger other logic. Use **gray code** counters or series resistors to limit number of outputs switching and current.

## ***Worst Case Loading and Timing Analysis***

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- Ground Bounce captured on an oscilloscope due to excessive chip currents and/or high **resistance** in PSU or ground plane.



## **What if you can't measure, simulate or take account of everything? : Soak Testing**

- When it is hard to factor in all the various parameters, manufacturers will sometimes resort to submitting each produced system to a **Soak test** as a way of weeding out **flaky systems** after assembly – but it's expensive, it's not a substitute for better design.
- Soak or “**Burn in**” Testing involves testing under **stress**, e.g. extremes of **Temperatures**, **Capacitive Loading** and **Supply Voltage** etc. This is particularly important in safety critical systems, e.g. **Nuclear Power Stations, Railway Signalling, fly by wire aircraft** etc. It also helps to identify systems that would fail early in their life.

## **Designing for Worst Case**

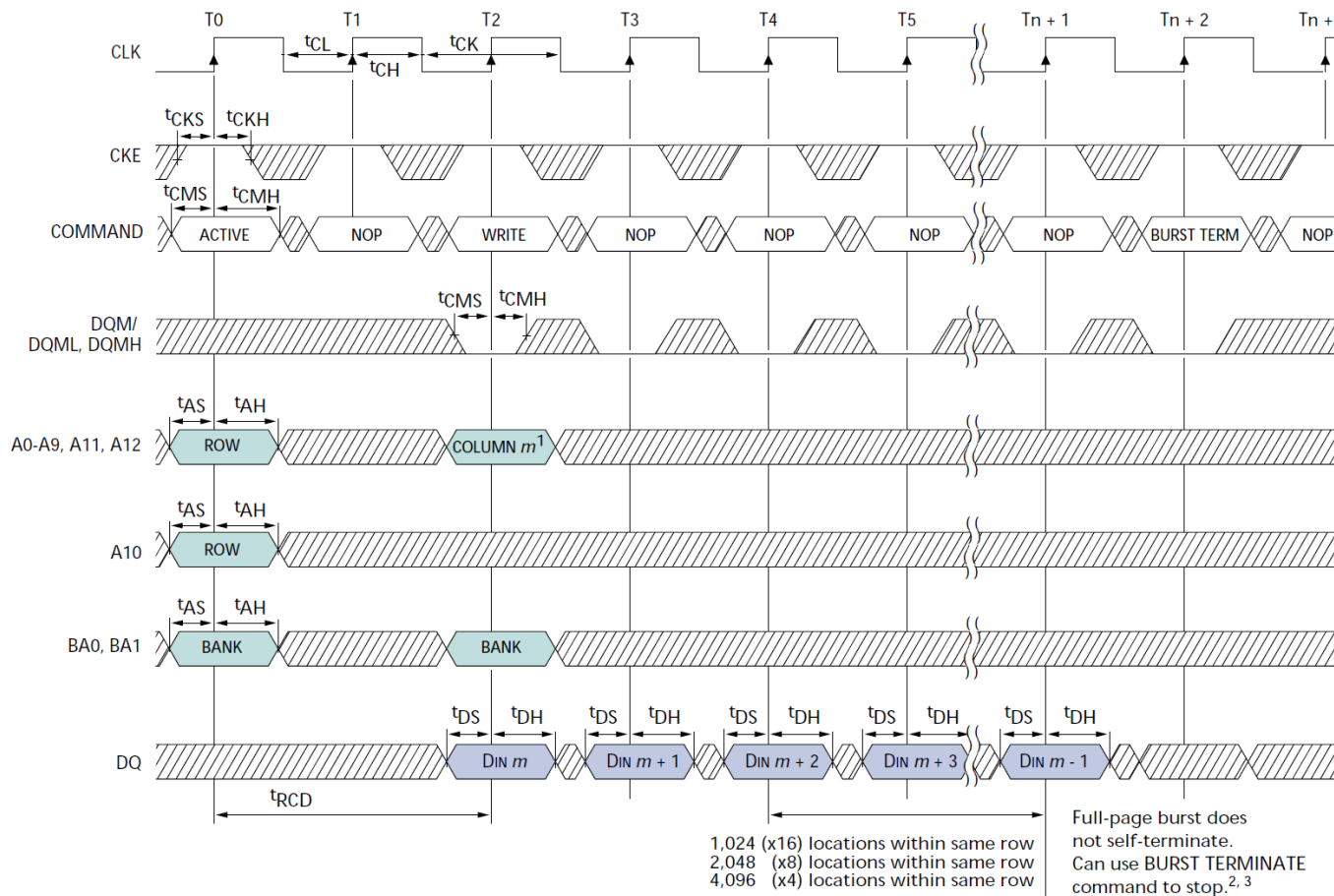
- A **worst case** design would attempt to take account of **as much** of the information that is available, as possible, regarding the **component** variations in **tolerances** and **timing**.
- If this approach is adopted, then even when **all** component parameters are at their most **adverse values**, or anywhere in between, a worst-case design in theory should **always work**.
- If such a detailed analysis, is **not** undertaken then there is no way of knowing if the design will work **reliably** when it is mass produced and subjected to differing environments.

# Worst Case Loading and Timing Analysis

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## Timing Diagrams

- To design for worst case, an Engineer must be able to understand and perform **detailed timing analysis** of **manufacturers data sheets**. Simulation results can then be **compared** to data sheets to **verify timing** (we do this in **Assignment 1**). Can you interpret this timing diagram, what do the signals and timing parameters mean and which of them are important?



An SDRAM  
Memory  
chip Timing  
diagram

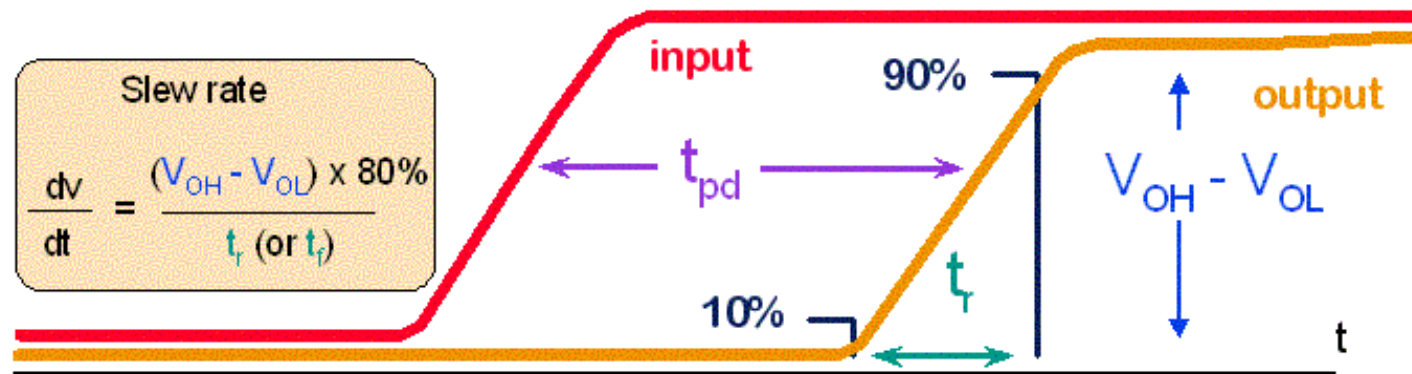
## **Timing Concepts**

- Every microcomputer system design engineer should also have a handle on at least the following very important timing concepts and what can cause them to vary.
- Knowledge of these is essential to an understanding of how to interface CPUs to say memory systems, motherboards and backplanes.

- Slew Rate of a signal.
- Propagation Delay (*Latency*) of a signal.
- Setup and Hold time (*Meta-stability issues*)

## ■ Slew rate: Causes and Effects on Timings

- The slew rate of an output signal is the **rate of change of its output voltage**  $dV/dt$ , or more usefully is quoted as the time it takes an IC to switch from say 10% ( $V_{OL}$ ) to 90% ( $V_{OH}$ ) and vice-versa of its final value i.e. from **logic 0** to **logic 1**.
- In other words, even if the circuit has made the decision **internally** as to what the output should be, it still takes time for the output transistor(s) to switch the end of the wire from one logic level to another.



## ■ **Factors affecting Slew Rates**

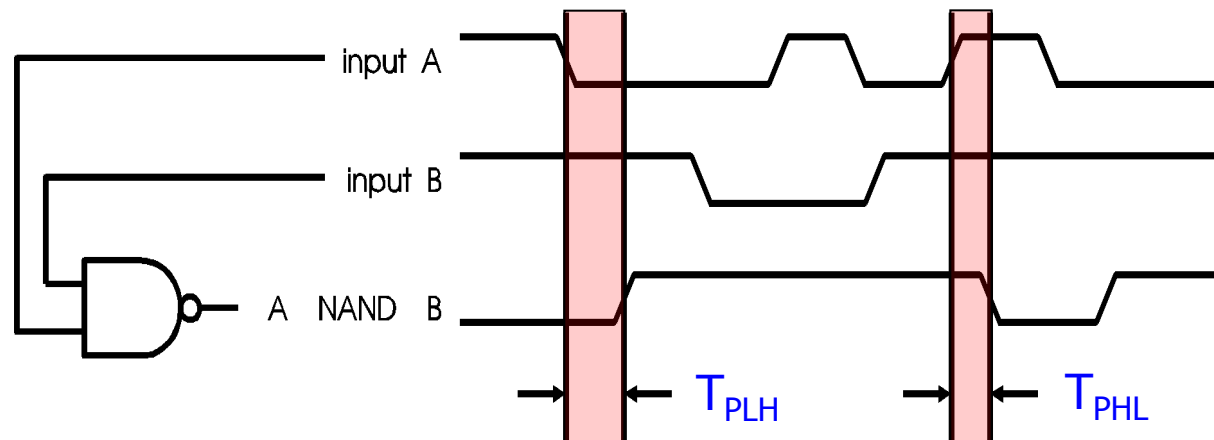
- A circuit has to **charge** and **discharge** the inherent **capacitance** of the load (**gates** and **PCB tracks**) connected to the output signal via the **output resistance** of the transistor driving the signal (*as well as fight the back emf due to the inductance of any wires attached to it*). Thus increased capacitive/inductive loads **slow** the '**rise**' and '**fall**' time of the signal.
- Manufacturers may quote the **rise** and **fall times** for an output signal but only a specific **capacitive load**. Differences, particularly in **capacitive load** can then be taken into account by you.
- **SIGNAL** rise/fall times proportional to  $e^{-(1/RC)}$
- The move to lower supply voltages (**3.3v** and more recently **1.8v**) means the 10% to 90% values are reduced, consequently **output signals switch state faster when designed to operate at lower voltages**. (*That's different to lowering the voltage from the one specified by the manufacturer*).

# Worst Case Loading and Timing Analysis

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## Propagation Delays (Latency)

- A **propagation delay** is a measure of the time taken for a change at the **input** of a device to effect a change at the **output**. Even **wires**, exhibit some delays.
- Not all devices have **symmetrical** delays for **positive** and **negative** transitions.
- In the diagram below, the propagation delays for a **high to low** transition ( $T_{PHL}$ ) are **shorter** than for a **low to high** transition ( $T_{PLH}$ ).
- This asymmetrical delay is common for **TTL** devices (**note CMOS devices tends to have more symmetrical timings**) **open collector** and **open drain** outputs because they are better at **sinking** current than **sourcing** it. Rise times for an open drain output are notoriously slow due to the **pull up resistor** being used to charge load capacitance.
- Serious timing issues can arise if a number of devices are cascaded all exhibiting their **min** (or **max**) propagation values. Under such circumstances, one signal can race another, perhaps overtaking it and arriving **before** (or **after**) it is required.





# Worst Case Loading and Timing Analysis

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Philips Semiconductors

Product specification

3-to-8 line decoder/demultiplexer; inverting

74HC/HCT138

## DC CHARACTERISTICS FOR 74HC

For the DC characteristics see *"74HC/HCT/HCU/HCMOS Logic Family Specifications"*.

Output capability: standard  
I<sub>CC</sub> category: MSI

Note rise and fall times specified for a particular capacitive load

## AC CHARACTERISTICS FOR 74HC

GND = 0 V; t<sub>r</sub> = t<sub>f</sub> = 6 ns; C<sub>L</sub> = 50 pF

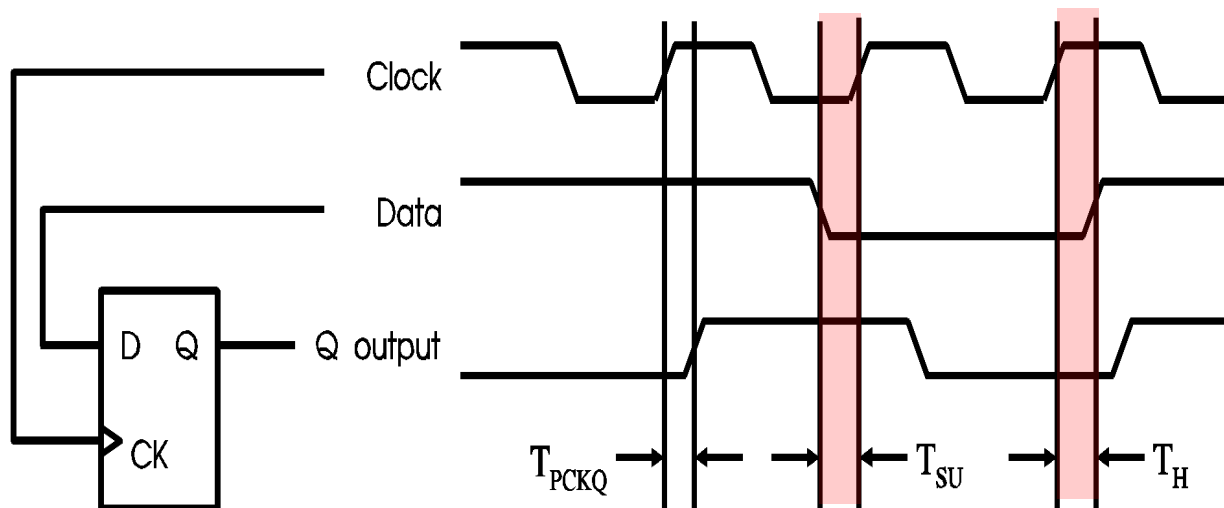
Note variation in times with temperature

SYMBOL	PARAMETER	T <sub>amb</sub> (°C)								UNIT	TEST CONDITIONS	
		74HC									V <sub>CC</sub> (V)	WAVEFORMS
		+25			−40 to +85		−40 to +125					
		min.	typ.	max.	min.	max.	min.	max.				
t <sub>PHL</sub> / t <sub>PLH</sub>	propagation delay A <sub>n</sub> to $\bar{Y}_n$		41 15 12	150 30 26		190 38 33		225 45 38	ns	2.0 4.5 6.0	Fig.6	
t <sub>PHL</sub> / t <sub>PLH</sub>	propagation delay E <sub>3</sub> to $\bar{Y}_n$		47 17 14	150 30 26		190 38 33		225 45 38	ns	2.0 4.5 6.0	Fig.6	
t <sub>PHL</sub> / t <sub>PLH</sub>	propagation delay $\bar{E}_n$ to $\bar{Y}_n$		47 17 14	150 30 26		190 38 33		225 45 38	ns	2.0 4.5 6.0	Fig.7	
t <sub>THL</sub> / t <sub>TLH</sub>	output transition time		19 7 6	75 15 13		95 19 16		110 22 19	ns	2.0 4.5 6.0	Figs 6 and 7	

Note variation in times with Voltage

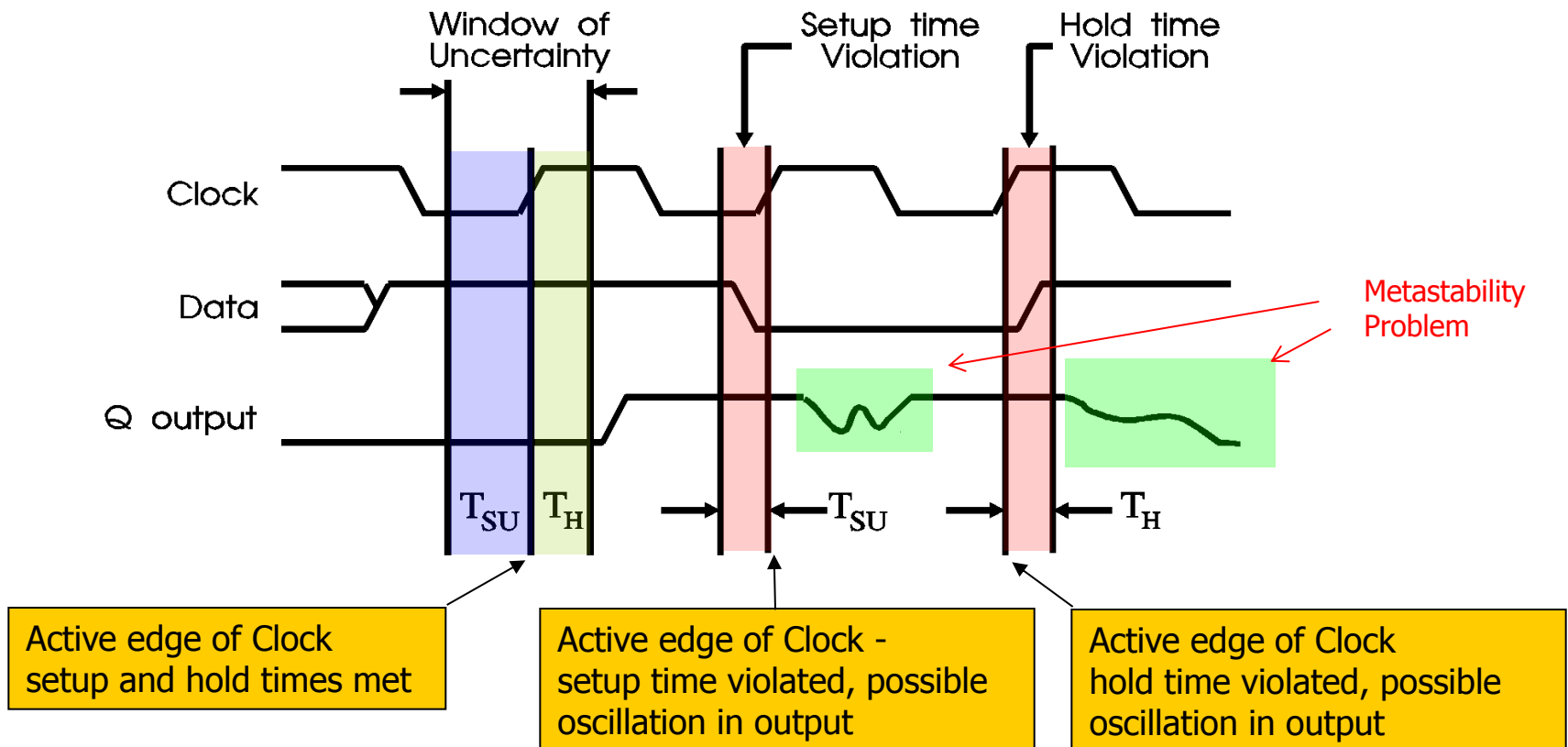
## Synchronous (clocked) Systems

- A huge problem in synchronous systems is ensuring that flip-flop **setup** and **hold** times are not violated
  - **Setup time** ( $T_{SU}$ ) is the length of time the Data input to the flip-flop must be **valid** and **stable, prior to being clocked**.
  - **Hold time** ( $T_H$ ) is the length of time the Data input to the flip-flop must be held **valid** and **stable, after being clocked**.
- If setup or hold times are violated, the **Q** output may become **invalid** or even **oscillate**, a condition referred to as **metastability** (see on-line Application note on metastability by Altera)



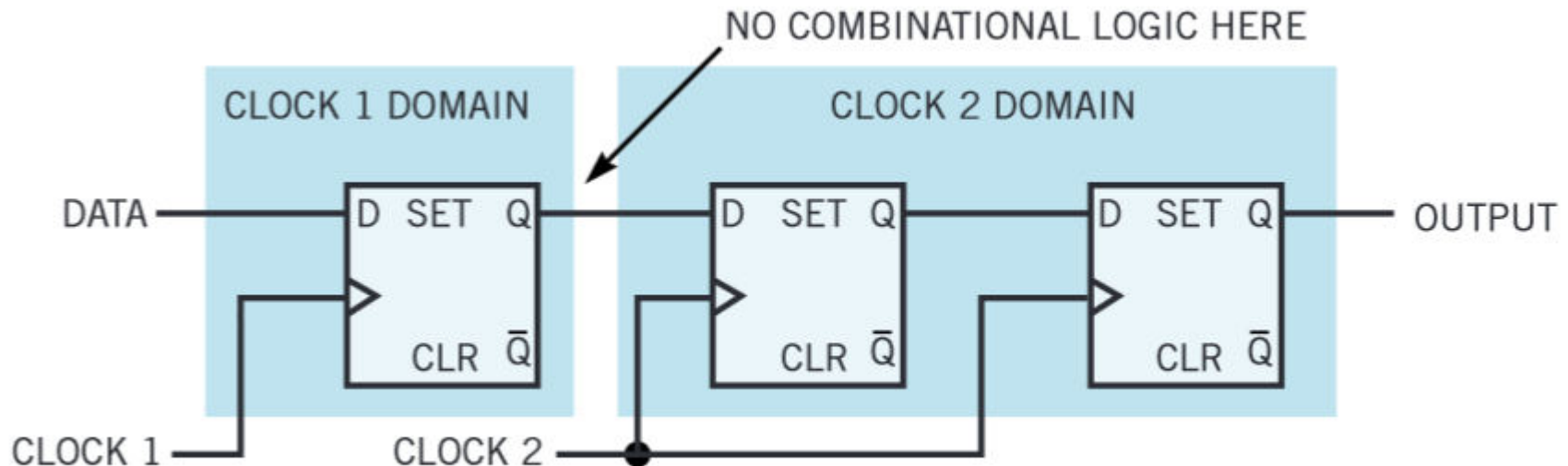
## Metastability

- The illustration below shows what *can* happen to the output of a Flip-Flop when it's **Set-Up** and/or **Hold-times** are **violated**. This is a particularly important consideration in synchronous (clock driven) systems.
- When either of these times is violated, the output may take an invalid level, or more commonly oscillate for an undefined period of time. (*Read article from Altera on course web-site*)



### **Tolerating Metastability**

- It has been shown that once a flip flop enters a meta stable state, the probability of being in that state some time later decreases exponentially with time.
- When an asynchronous input arrives at a flip flop, perhaps from the real world, or from another circuit driven by a different clock (i.e. a signal crosses a clock domain) there is a possibility that it will induce metastability. The probability of this problem propagating to another part of the circuit can be reduced by having synchronising logics, such as that shown below.



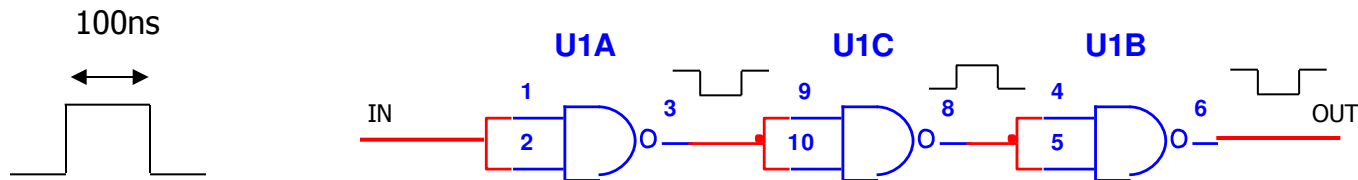
Synchronizer circuit

<http://m.eet.com/media/1137372/17561-310388.pdf>

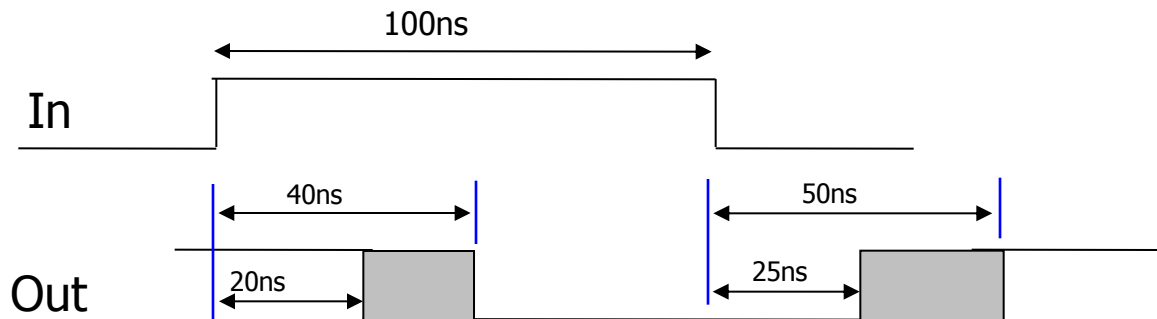
# Worst Case Loading and Timing Analysis

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- Draw the min/max timing diagram for the output of the following circuit assuming nominal temperature and voltage supply and no adverse capacitive loading on any output.



**Solution:**

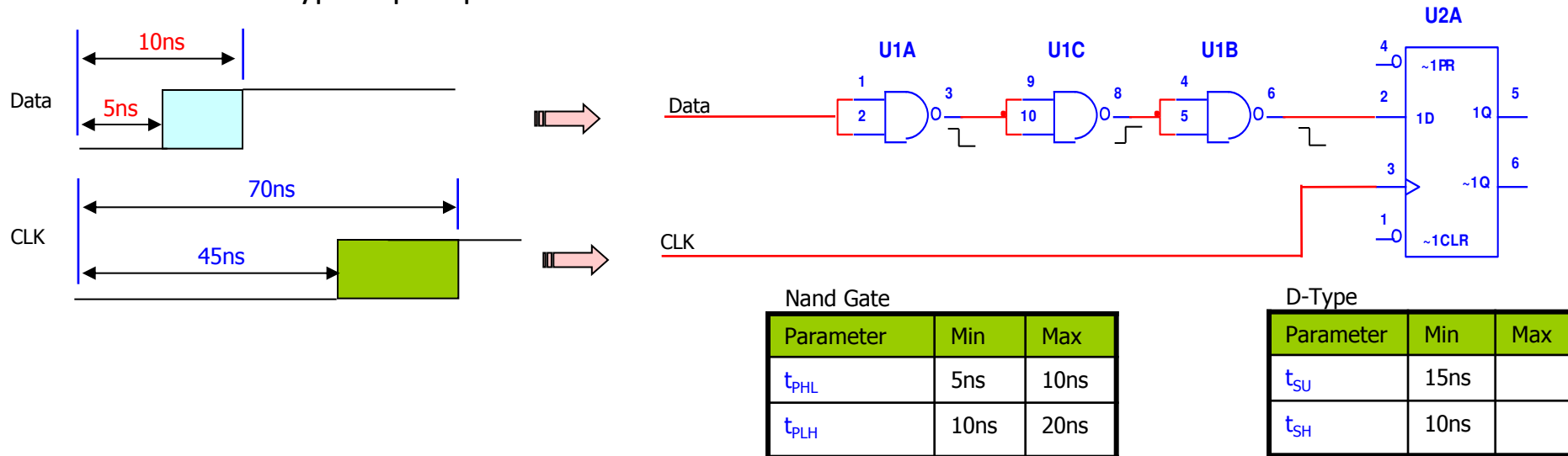


Parameter	Min	Max
$t_{PHL}$	5ns	10ns
$t_{PLH}$	10ns	20ns

# Worst Case Loading and Timing Analysis

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Given the timing variation inherent in the Data signal below, is it possible that the **Setup** or **Hold time** of the D-Type Flip Flop could be violated?



**Solution:** This is a classical 'race' problem where the **Data** at the flip flop must arrive at least **15ns** (worst case setup time) before the 'Clock'. First calculate the variation in signal timing at the 'D' input to the flip-flop

The fastest path to the D input signal is  $5 + 5 + 10 + 5 = 25ns$

The slowest path to the D input signal is  $10 + 10 + 20 + 10 = 50ns$ .

To violate the **setup time**, the **CLK** signal would need to change less than **15ns** after data. One possible example is that the data is at its slowest (**50ns**) and the **CLK** changes anywhere between **50ns** and **65ns**

To violate the **Hold time** the D would need to change within **10ns** of the clock arriving. This is possible if the data is slow and arrives at say **50ns** and the clock arrives at **45ns**.